

A High Performance Scintillator Ion Beam Monitor (SBM)*



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* The SBM is a patented invention by Integrated Sensors, LLC.
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System Overview

Motivation

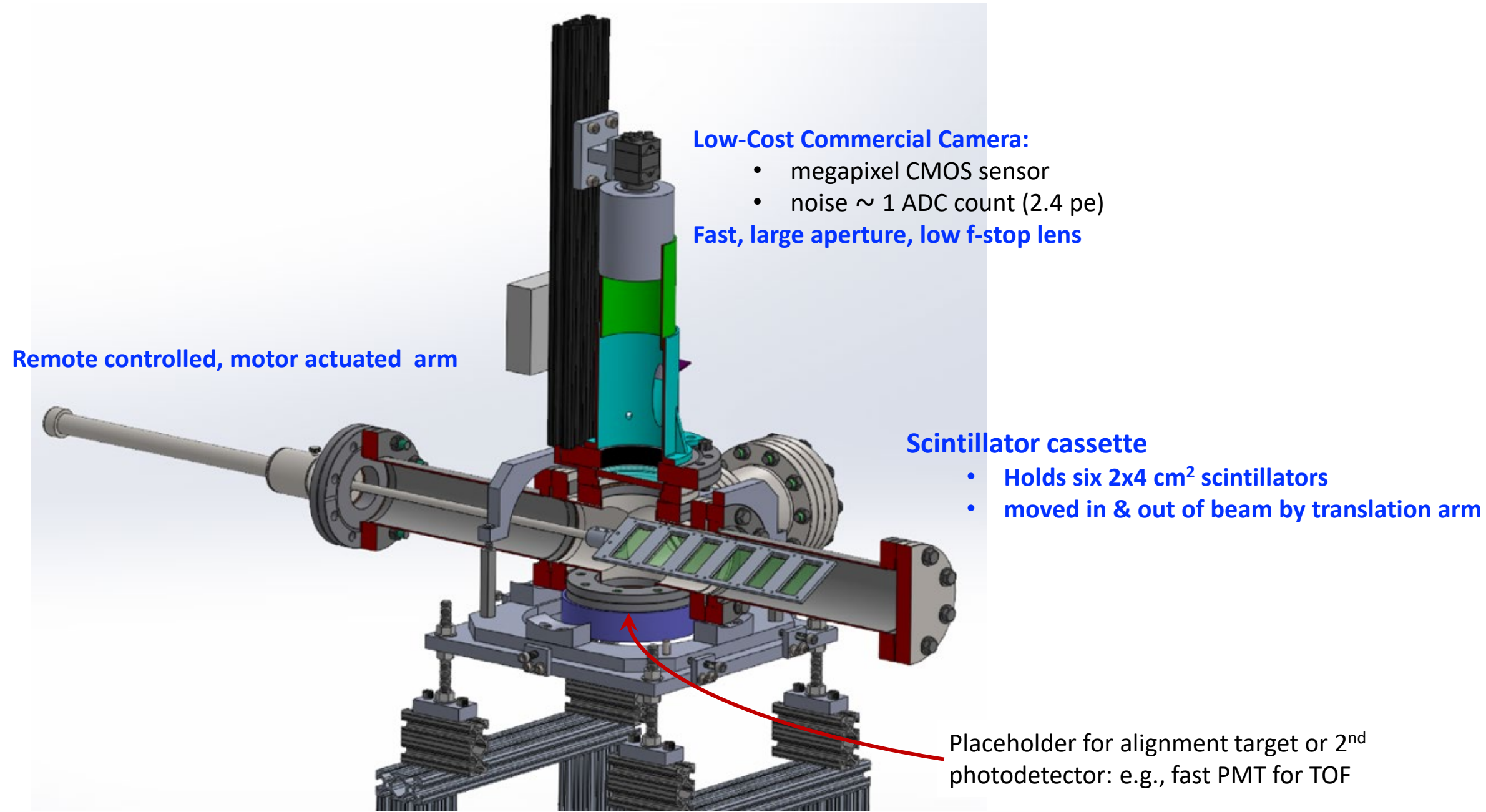
I. Precision beam analysis // display results in real-time

← this presentation

II: related to high dose rate (FLASH) radiotherapy beam monitoring (PTCOG60-Miami, FRPT21-Vienna, FRPT22 Barcelona)

Main Features

- Novel-use thin scintillators: very high sensitivity, clean imaging
- Scintillators are insertable/retractable without breaking vacuum using translation arm
- High resolution beam imaging : beam centroids, widths, amplitudes
- Thin, low low mass scintillators: higher energy beams are transmissive
- Wide dynamic range of ion currents: single ions (at low energy) to nA/cm^2

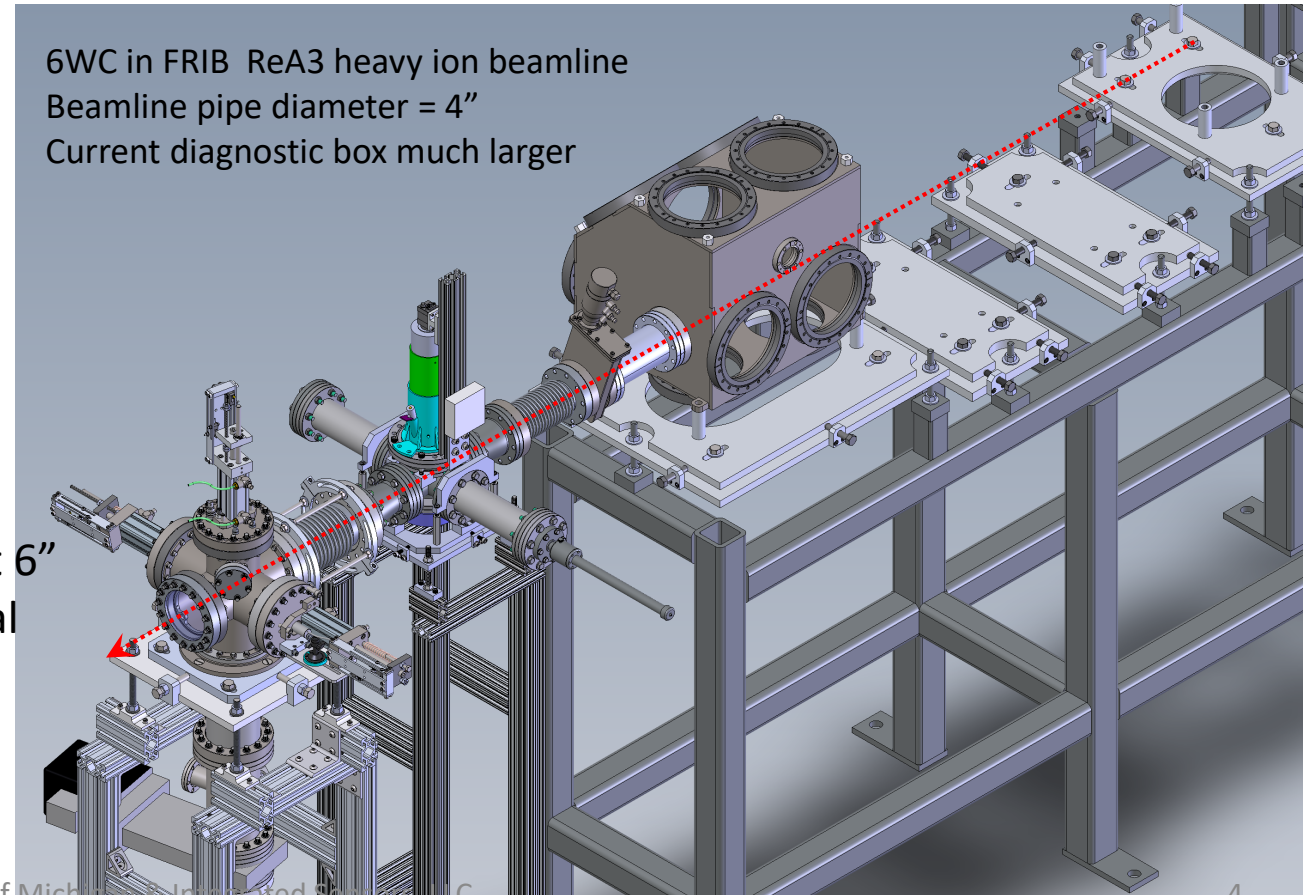
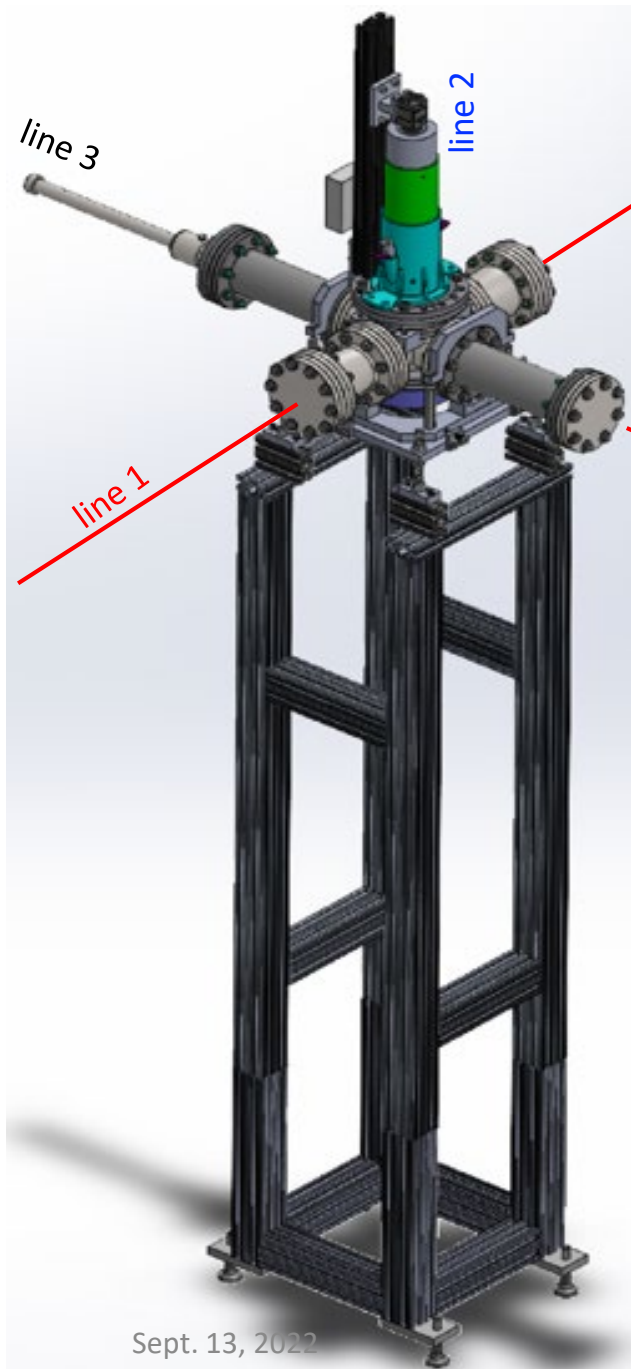


SBM configured as "Six-Way-Cross" (6WC) with 3 orthogonal lines

Line 1: beam path (vacuum) fore/aft

Line 2: optical: light paths to camera top + alignment targets bottom

Line 3: scintillator ladder travel



Only about 6"
longitudinal
footprint

Scintillators - Two types of thin, non-hygrosopic and radiation resistant materials*

Type 1: Polymer Material (PM): a semicrystalline, organic plastic polymer

- superior physical properties: tough, thin to ultra-thin, can cover large areas
- high light emittance --> observed large amplitude signals compared to polyvinyltoluene (& polystyrene) based plastic scintillators
- semicrystalline → hazy appearance, no internal reflections, more light escapes the surfaces
- available in variety of thickness. We tested 1 μm to 200 μm .
- thin films attractive for transmissive beam applications (e.g., continuous beam monitoring & radiotherapy)

Type 2: Hybrid Material (HM): Inorganic polycrystalline ceramic hybrid

- active layer embedded in a polymer matrix. Support substrate and protective polymer layer
- available in large area sizes & thinner than single crystal CsI(Tl), (e.g. < 0.5 mm)
- high light emittance: generates significantly larger amplitude signals than CsI(Tl)
- no internal reflections

PM and HM are designed and widely used for other purposes

* Four patents issued to Integrated Sensors on PM & HM materials for beam monitoring applications.

DAQ - Display System

Image processing:

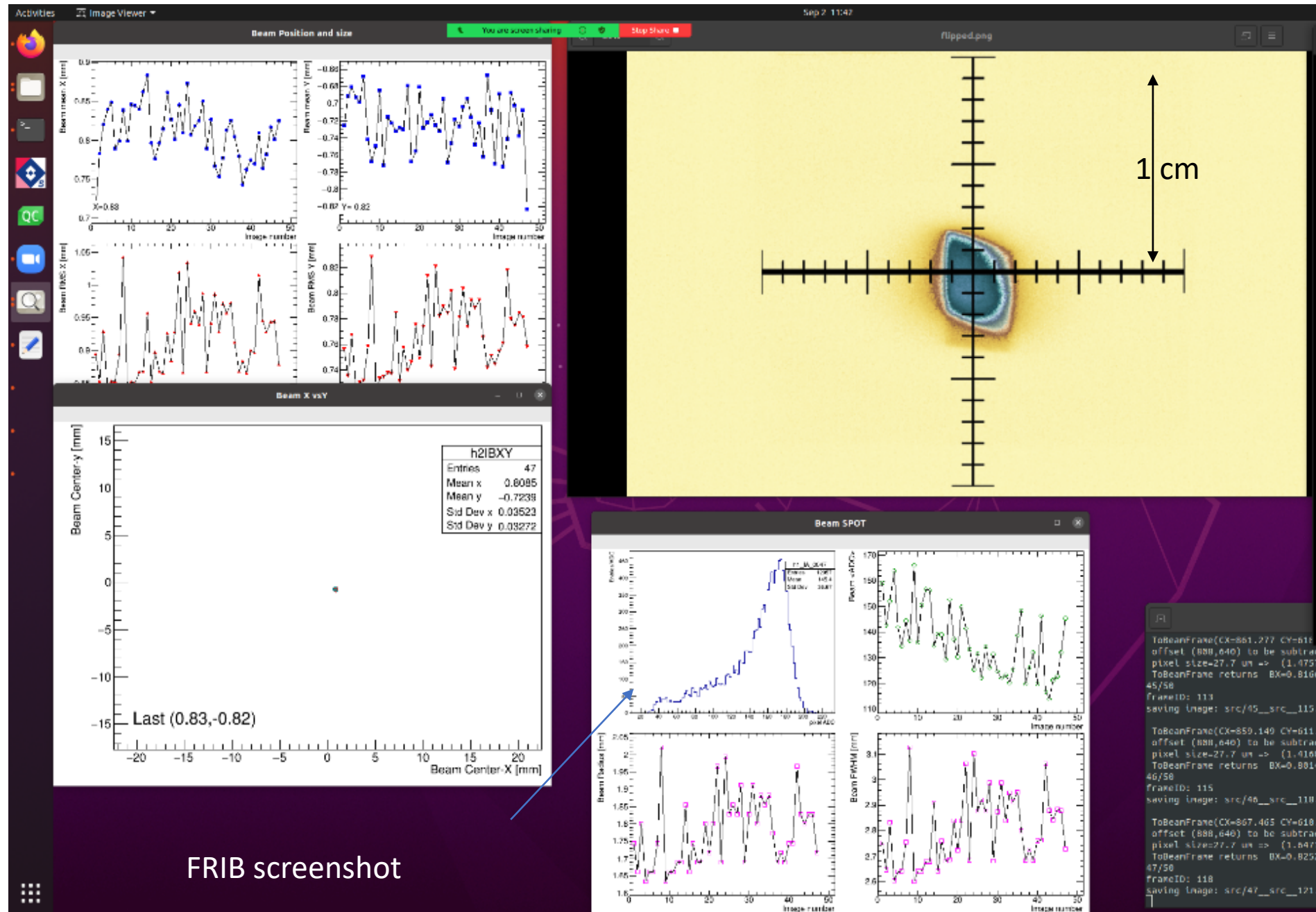
- background subtraction
- faulty pixel removal
- perspective & rotation transformations
- ➔ display in beam coords

Analysis:

- beam finding
- beam profiling (centroids, widths)
- peak amplitude

Display

- False color image
- real-time analysis
- updating graphics

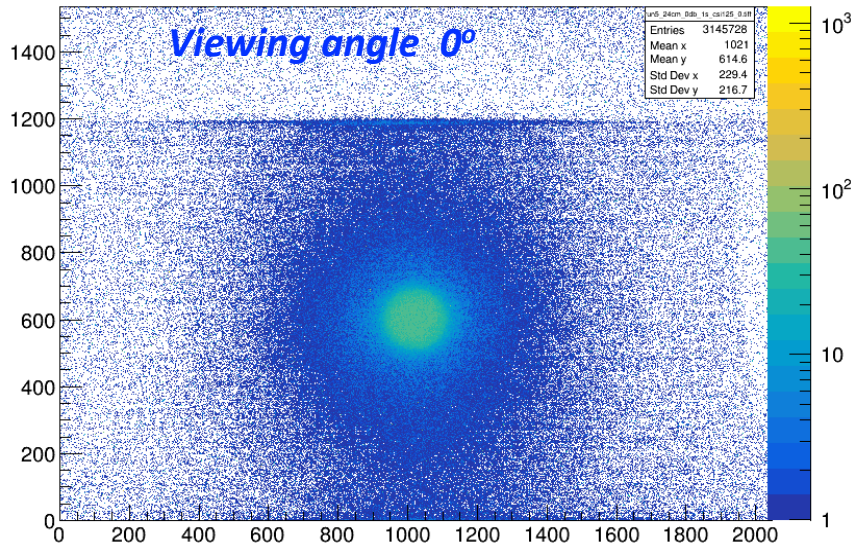


FRIB screenshot

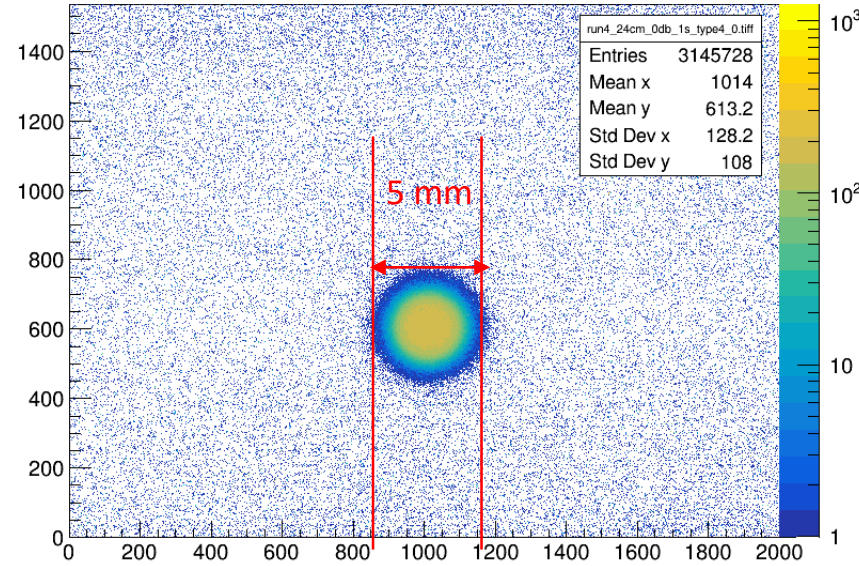
Test Results

Location	Source	Energy [MeV/n]
UM Lab Testbench	β (^{90}Sr)	~ 1
Facility for Rare Isotope Beams (FRIB)	$^{86}\text{Kr}^{+26}$	2.75
Michigan Ion Beam Laboratory (MIBL)	p	1 - 6
Notre Dame Radiation Laboratory (NDRL)	e^-	8

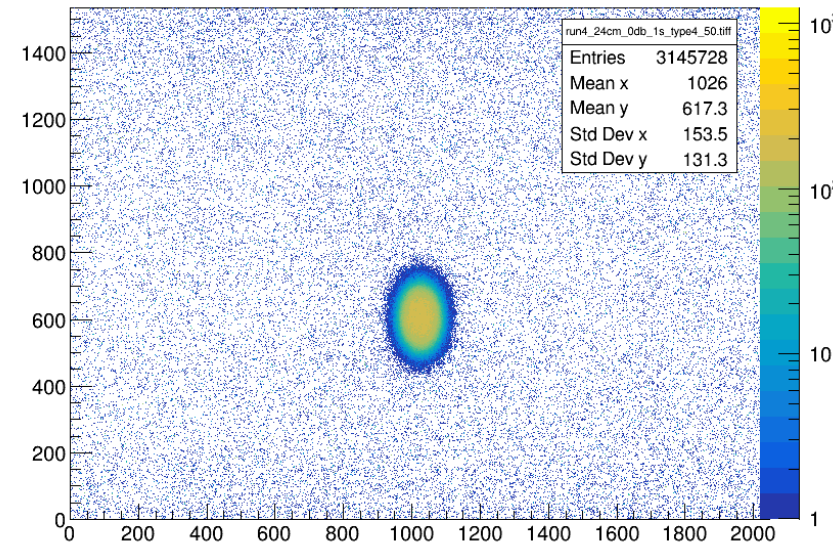
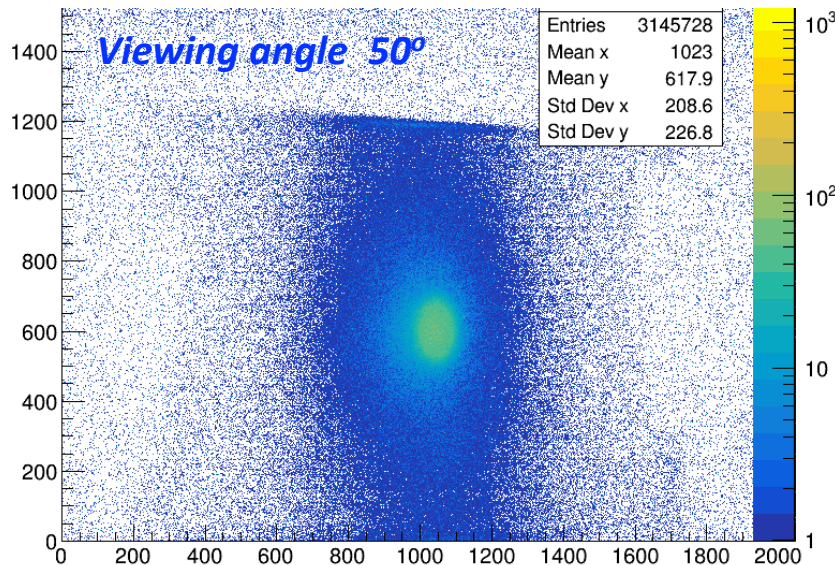
UM Benchtest of Scintillators: Compare HM to CsI(Tl) single crystal



CsI unpolished, 1.25 mm



HM 435 μm



- Result 1:**

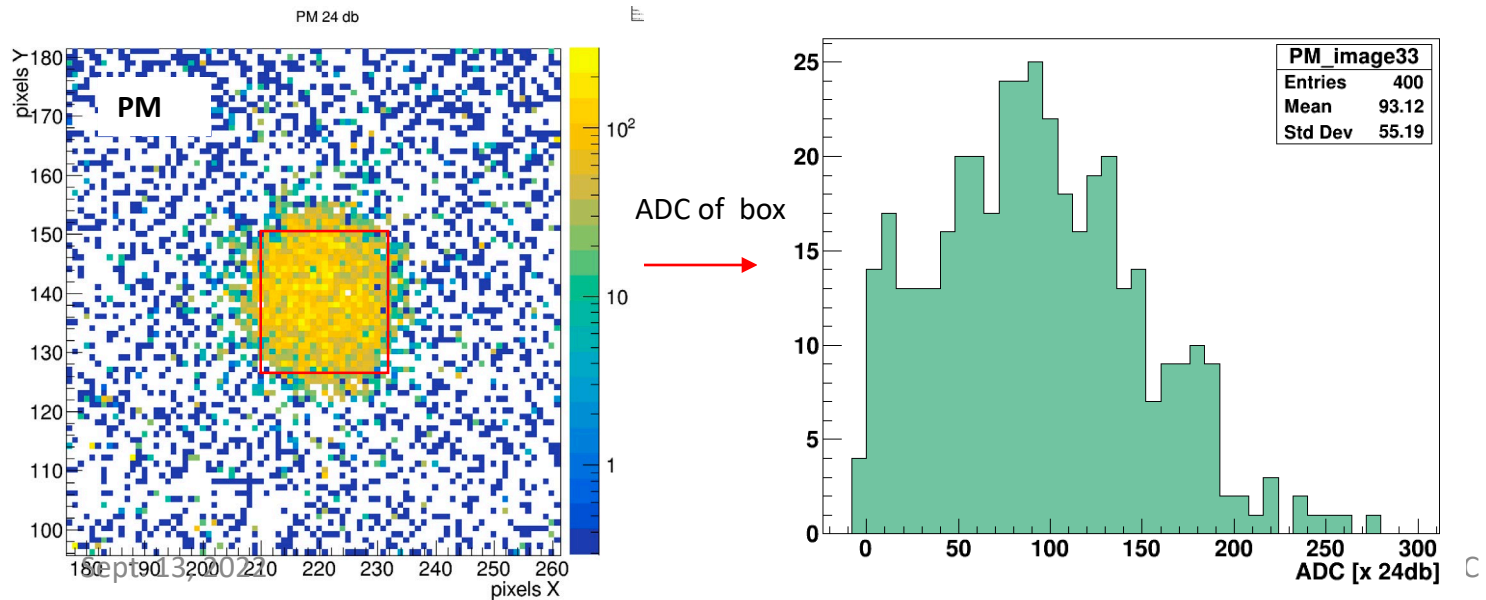
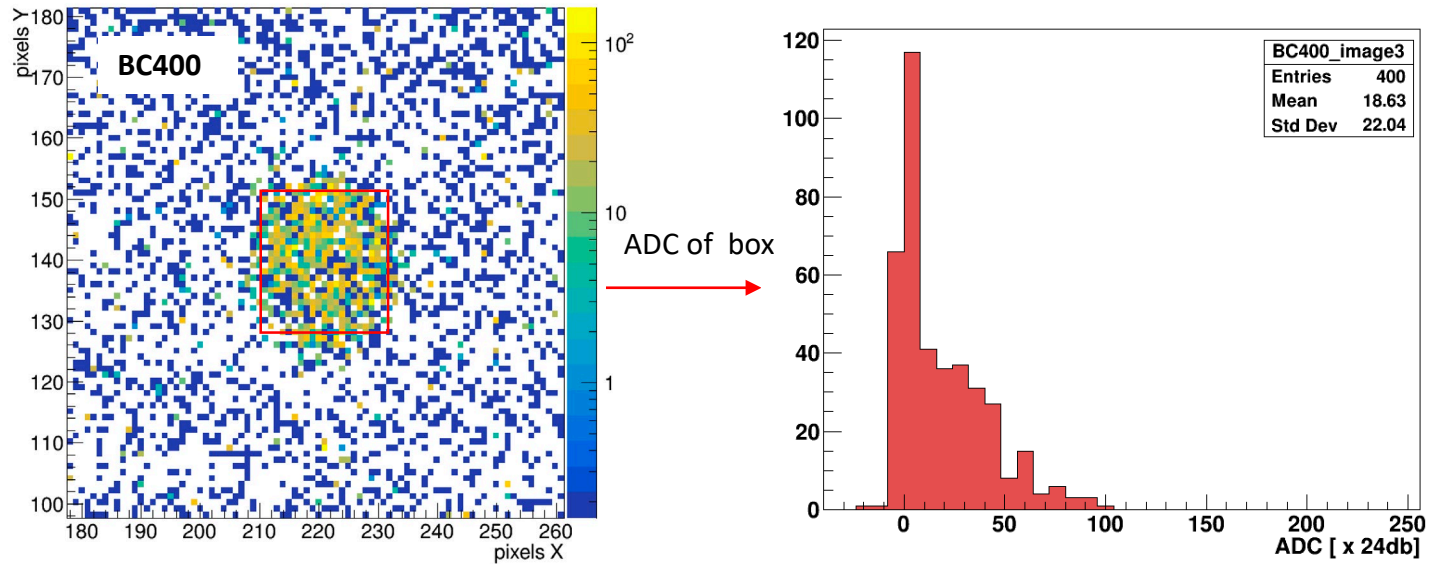
HM offers a clean beam image: free of reflections, blooming, distortion & sidewall emissions

- Result 2:**

HM/CsI(Tl) relative signal strength normalized to material thickness:
(ADC/mm) at 0° 12x

UM Lab Test of Scintillators: Compare PM to BC400

~200 μm thick + ^{90}Sr source + 1 s exposures + 24 dB pixel gain



Result:

BC400 (PVT based):
image more sparse hit distribution,
weak signal

PM:
Clean image with well delineated source
robust signal above background.

Mean ratio of PM/BC-400 ~ 5x (93:19)

Facility for Rare Isotope Beams (E. Lansing, Mich) (FRIB ReA3 beamline)

Project objective: provide FRIB with advanced & fast beam monitoring.

effective cost of beam operations: \geq \$20K/hr \rightarrow high premium for fast tuning technology

- Ion: $^{86}\text{Kr}^{+26}$ at 2.75 MeV/n (236 MeV/nucleus)
- Current: 5- 10 pps (single particles) up to 520,000 pps

Selected results:

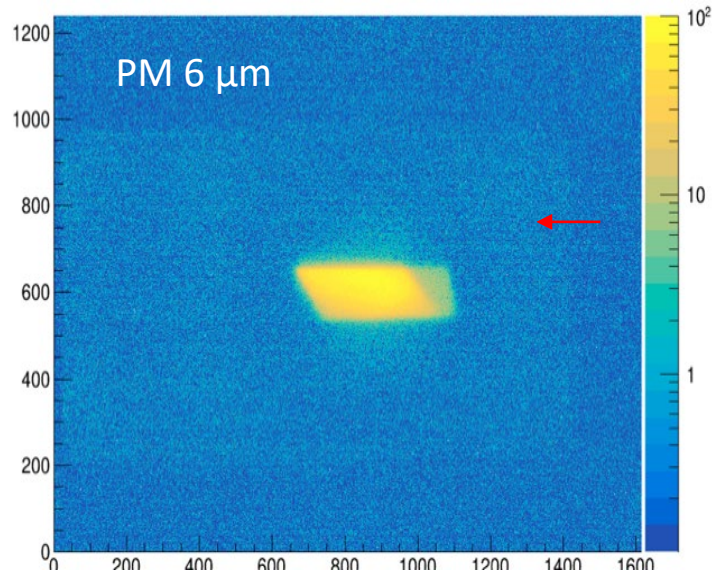
1. PM scintillators

- Beam imaging
- Signal amplitude vs thickness
- Signal amplitude vs current
- Transmission

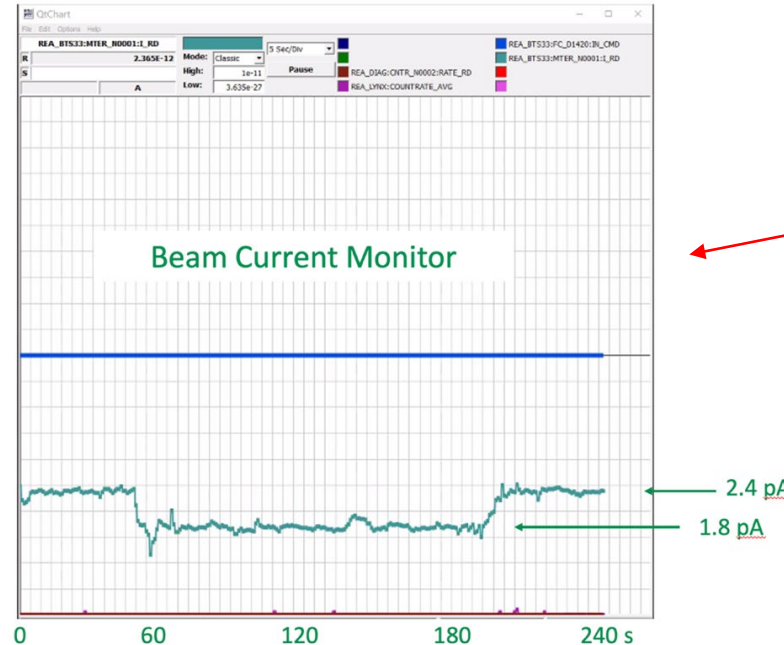
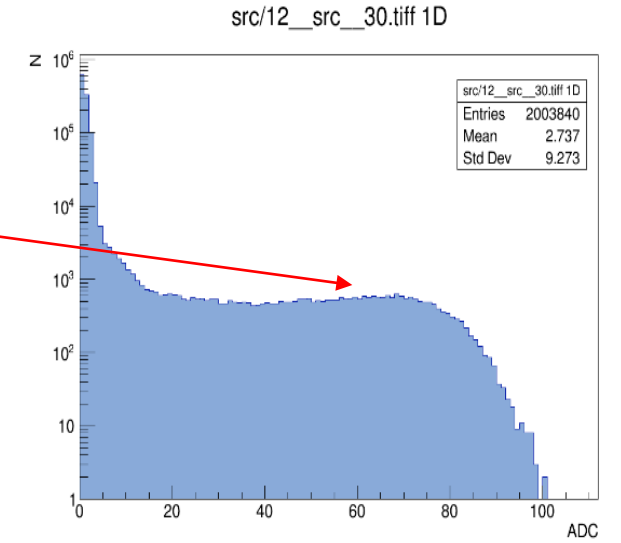
2. HM type scintillator:

- Single particle detection
- Response vs beam current
- Beam tracking & profiling

Signal and Beam Imaging in PM: beam current = 520,000 pps



6 μm PM still shows clean beam profile with ~43% of the 75 μm PM ADC_{max} signal



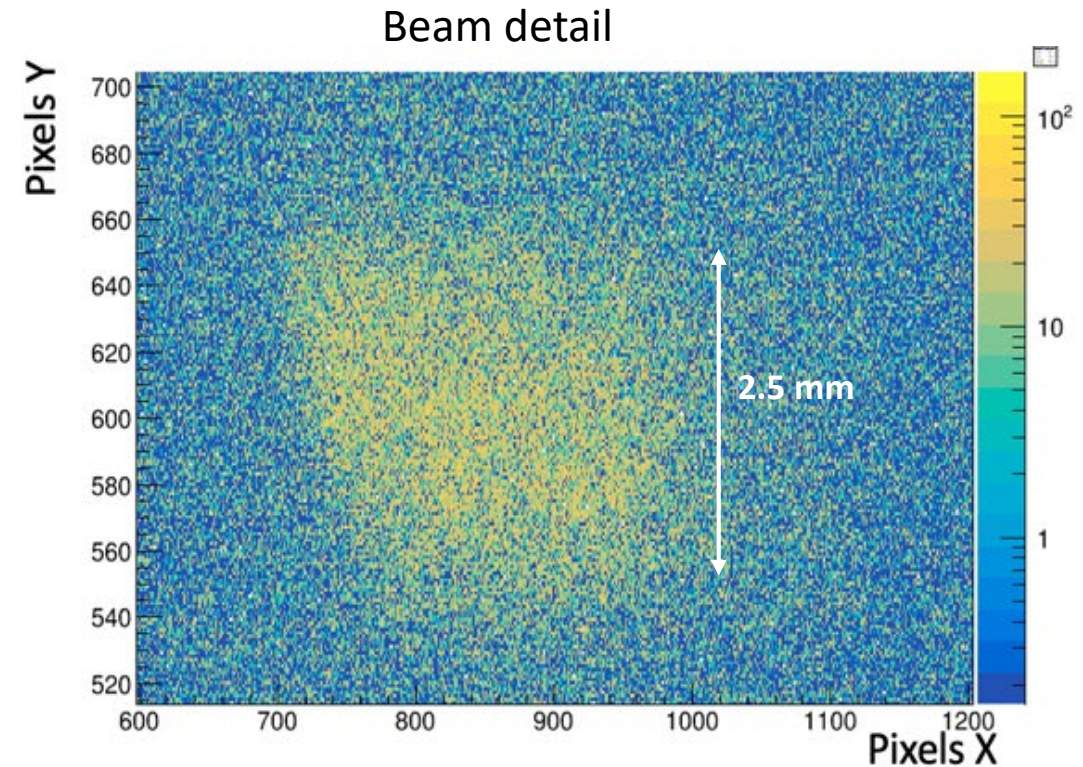
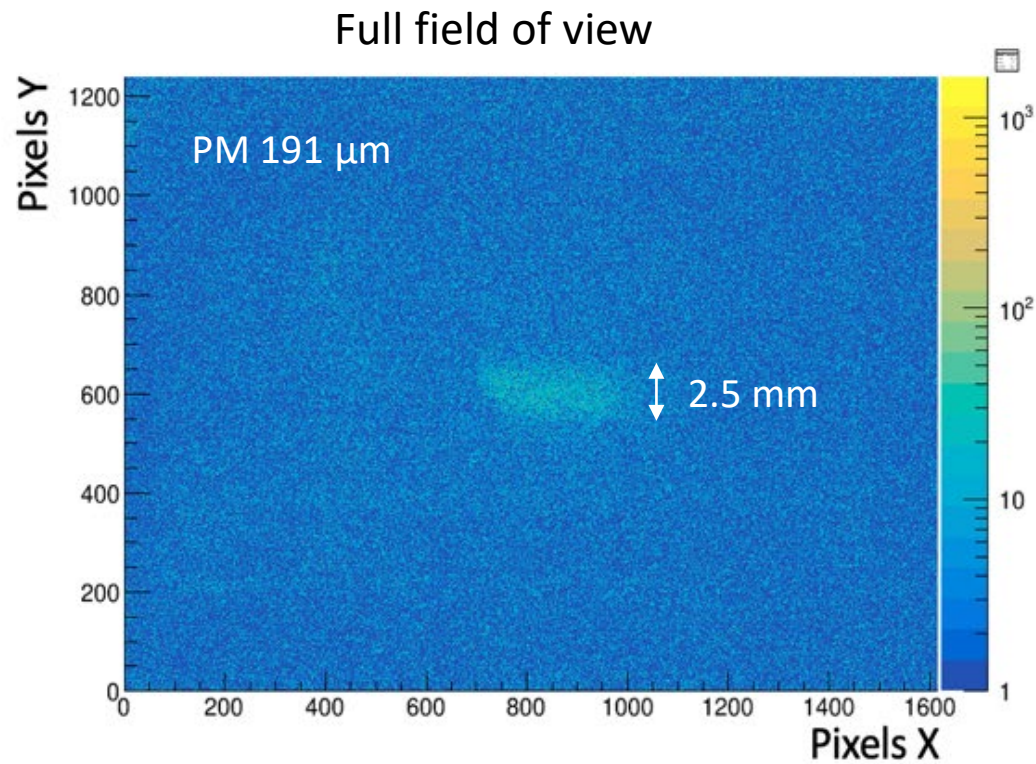
Beam current measured with Faraday Cup behind scintillator:

with 6 μm PM

→ 75% transmissive of ⁸⁶Kr 3 MeV/n

→ Energy loss = 42 MeV (from 236 MeV initial)

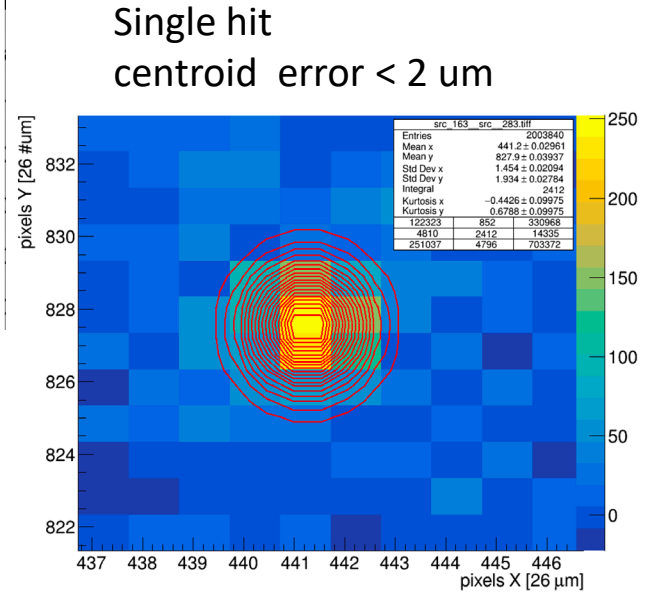
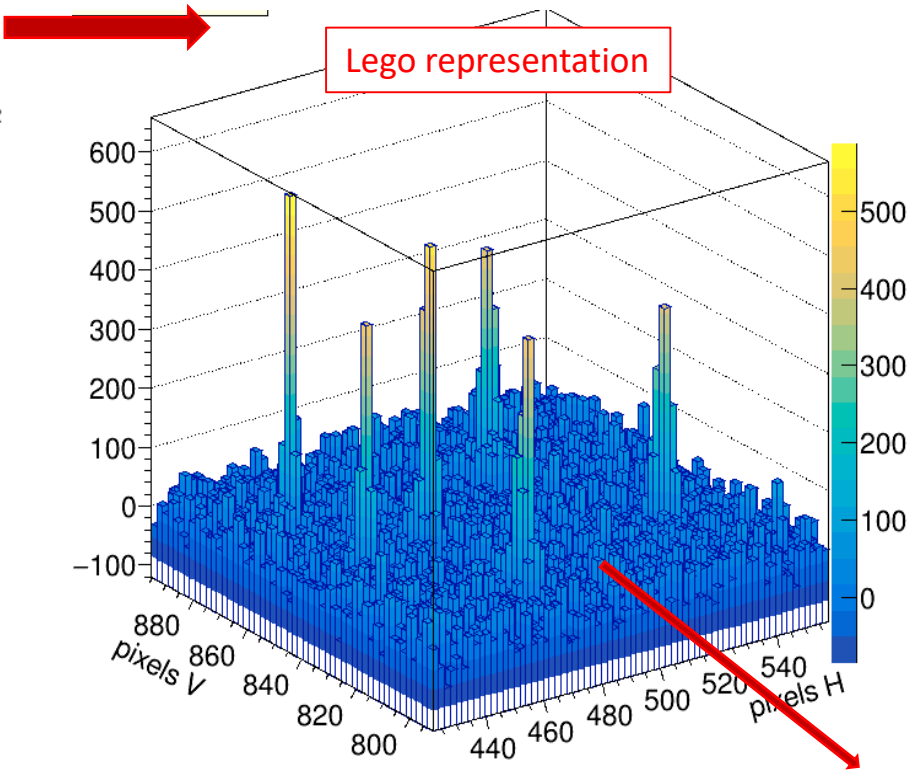
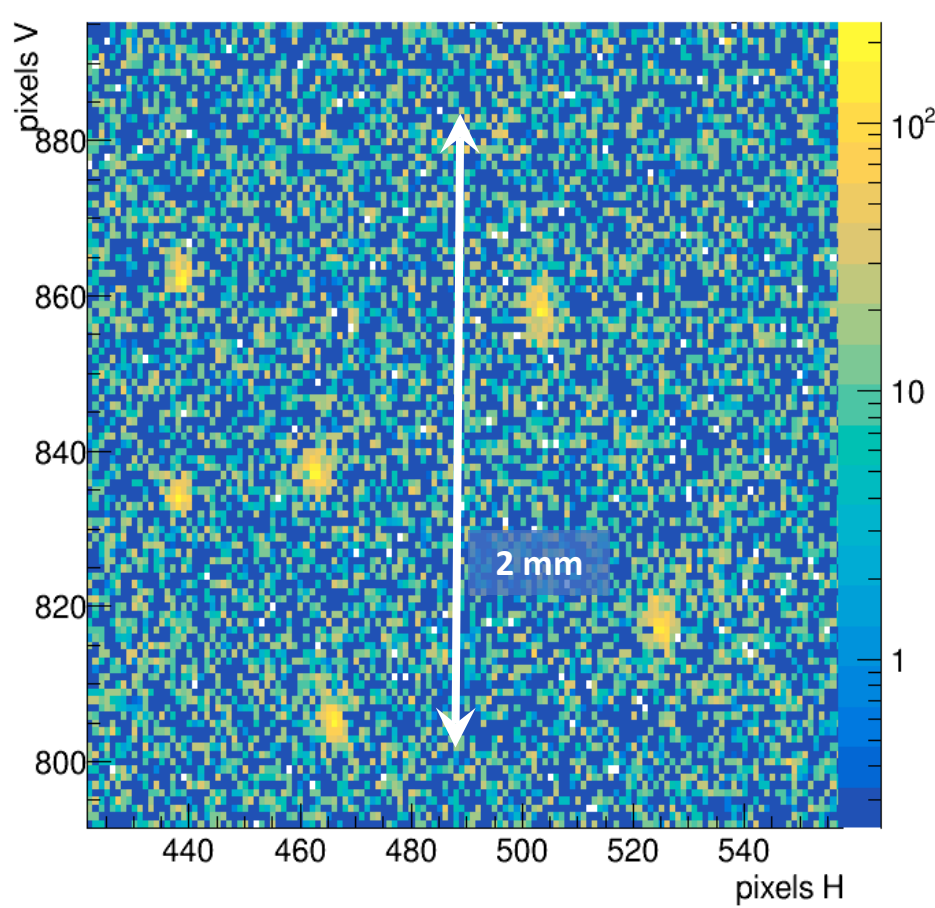
Signal and Beam Imaging in Thin PM Scintillator --> *reduce beam current 100X to 4.9 kHz*



Result 1: Clean beam profile is imaged. ADC signals well above noise

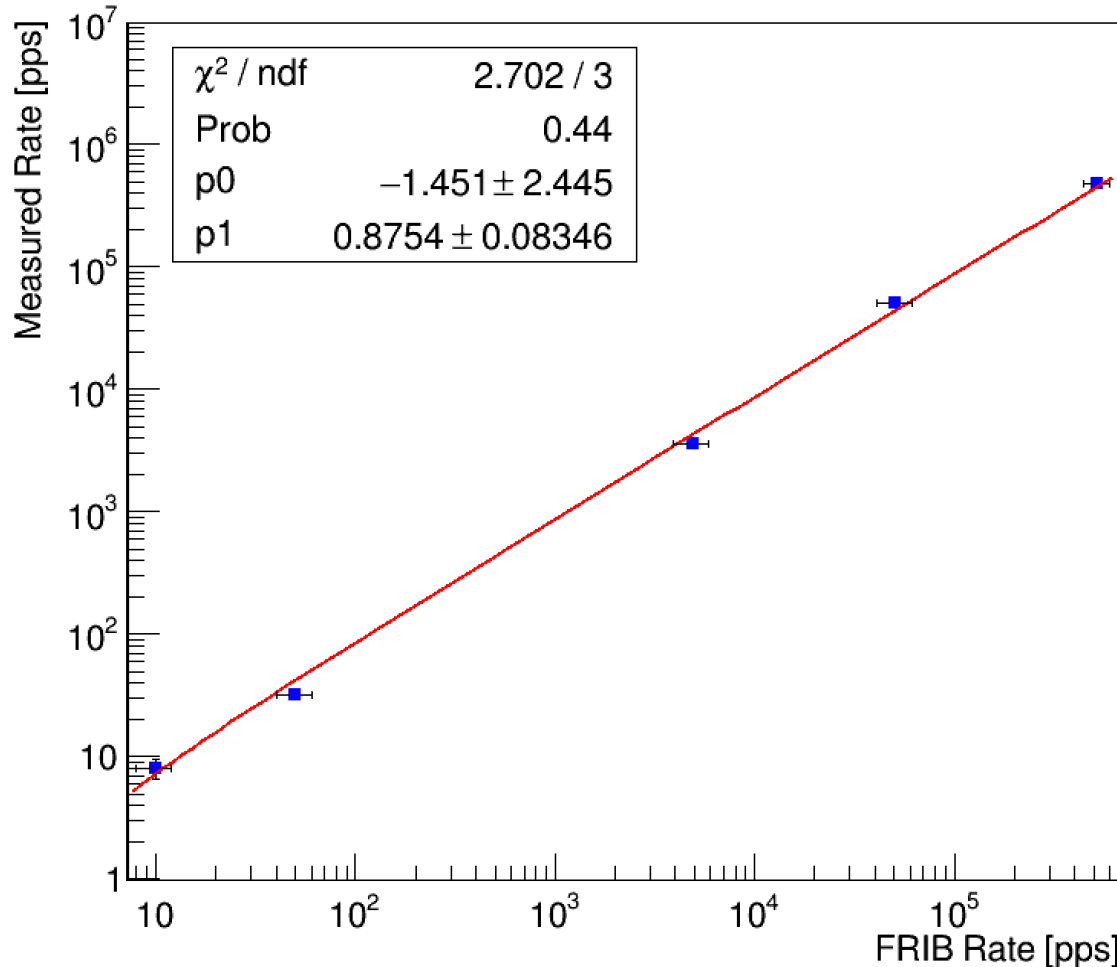
Result 2: Another $\sim 5x$ reduction to ~ 1 kHz beam currents would be detectable

Signal and Beam Imaging in HM Scintillator: Beam set to 5 – 10 Hz



Beam current in HM scintillator:

Measured rate vs FRIB “given” rate



Result 1:

The SBM can measure beam currents that are now determined by 4 different FRIB devices:

- Faraday Cup
- Calibrated beam attenuator
- MCP detector
- Silicon detector

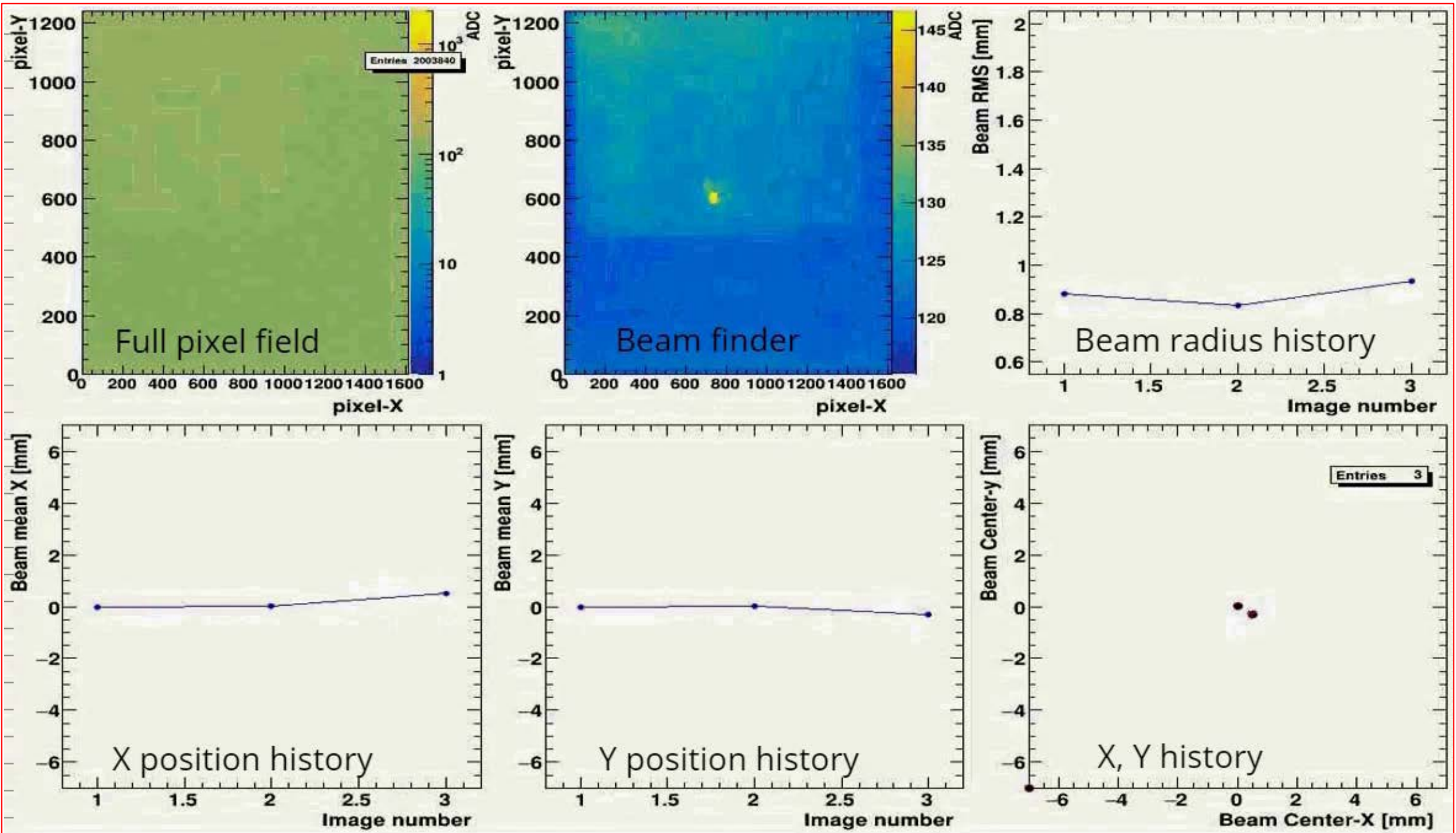
Result 2:

SBM measurement is linear over 5 orders-of-magnitude

Beam finding, profile analysis & display in real-time

Conditions:

- 1) Beam current 50 pps – *very low rate*. → *use HM scintillator*
- 2) *Beam width ~ 2 mm*
- 3) *Beam moved in square pattern by control room operations*
- 4) *1 s frames*



Conclusion

1) SBM provides a precise beam profiling in real-time ($\lesssim 1$ Hz)

2) Data from:

FRIB -- linear to *at least 5 orders-of-magnitude* for $^{86}\text{Kr}^{+26}$

MIBL -- 1-6 MeV protons $\sim 10^{11}$ pps/cm² 

NDRL -- 8 MeV pulsed **electron** beams to 4×10^{11} pps/cm²

==> response range: single particles to 10^{11} pps without breaking vacuum

3) PM: thin to ultra-thin materials produce clean imaging and accurate profiling

- Ultra-thin PM tested: from ~ 1 - 200 μm sample thickness
- **HM: *order-of-magnitude higher signal output*** compared to a much thicker CsI(Tl) standard

→ allows for very high sensitivity (single particles) at FRIB etc.

